

## **OptiMOS**<sup>TM</sup>3 Power-Transistor

#### **Features**

- N-channel, normal level
- Excellent gate charge x R<sub>DS(on)</sub> product (FOM)
- Very low on-resistance R<sub>DS(on)</sub>
- 175 °C operating temperature
- Pb-free lead plating; RoHS compliant
- Qualified according to JEDEC<sup>1)</sup> for target application
- Ideal for high-frequency switching and synchronous rectification
- Halogen-free according to IEC61249-2-21

Туре	IPD122N10N3 G
	1 2 (tab)
Package	PG-TO252-3
Marking	122N10N

## Maximum ratings, at $T_i$ =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	ID	T <sub>C</sub> =25 °C <sup>2)</sup>	59	А
		T <sub>C</sub> =100 °C	42	1
Pulsed drain current <sup>2)</sup>	I <sub>D,pulse</sub>	T <sub>C</sub> =25 °C	236	
Avalanche energy, single pulse	E <sub>AS</sub>	$I_{\rm D}$ =46 A, $R_{\rm GS}$ =25 $\Omega$	70	mJ
Gate source voltage	$V_{GS}$		±20	V
Power dissipation	P <sub>tot</sub>	T <sub>C</sub> =25 °C	94	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$		-55 175	°C
IEC climatic category; DIN IEC 68-1			55/175/56	

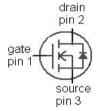
<sup>1)</sup>J-STD20 and JESD22

#### **Product Summary**

V <sub>DS</sub>	100	V
$R_{\mathrm{DS(on),max}}$	12.2	mΩ
I <sub>D</sub>	59	Α







<sup>&</sup>lt;sup>2)</sup> See figure 3



Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	
Thermal characteristics						
Thermal resistance, junction - case	$R_{\mathrm{thJC}}$		-	-	1.6	K/W
Thermal resistance,	$R_{thJA}$	minimal footprint	-	-	75	
junction - ambient		6 cm <sup>2</sup> cooling area <sup>3)</sup>	-	-	50	

## **Electrical characteristics,** at $T_i$ =25 °C, unless otherwise specified

#### **Static characteristics**

Drain-source breakdown voltage	$V_{(BR)DSS}$	$V_{\rm GS}$ =0 V, $I_{\rm D}$ =1 mA	100	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS}=V_{\rm GS}$ , $I_{\rm D}=46~\mu{\rm A}$	2	2.7	3.5	
Zero gate voltage drain current	I <sub>DSS</sub>	$V_{\rm DS}$ =100 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =25 °C	-	0.1	1	μΑ
		V <sub>DS</sub> =100 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =125 °C	-	10	100	
Gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =20 V, V <sub>DS</sub> =0 V	-	1	100	nA
Drain-source on-state resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =10 V, I <sub>D</sub> =46 A	-	10.5	12.2	mΩ
		V <sub>GS</sub> =6 V, I <sub>D</sub> =23 A	-	13.1	23.1	
Gate resistance	R <sub>G</sub>		-	1.1	-	Ω
Transconductance	$g_{fs}$	$ V_{\rm DS}  > 2 I_{\rm D} R_{\rm DS(on)max},$ $I_{\rm D} = 46~{\rm A}$	29	57	-	s

 $<sup>^{3)}</sup>$  Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm $^{2}$  (one layer, 70  $\mu$ m thick) copper area for drain connection. PCB is vertical in still air.



Parameter	Symbol Conditions		Values			Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	Ciss		-	1880	2500	рF
Output capacitance	Coss	$V_{GS}$ =0 V, $V_{DS}$ =50 V, $f$ =1 MHz	-	330	439	]
Reverse transfer capacitance	Crss		-	14	-	
Turn-on delay time	$t_{d(on)}$		-	14	-	ns
Rise time	t <sub>r</sub>	V <sub>DD</sub> =50 V, V <sub>GS</sub> =10 V,	-	8	-	1 - 1
Turn-off delay time	$t_{d(off)}$	$I_{\rm D}$ =46 A, $R_{\rm G,ext}$ =1.6 $\Omega$	-	24	-	
Fall time	t <sub>f</sub>		-	5	-	
Gate Charge Characteristics <sup>6)</sup>		<u> </u>		I _		T.
Gate to source charge	Q <sub>gs</sub>		-	9	-	nC
Gate to drain charge	Q <sub>gd</sub>	$V_{\rm DD}$ =50 V, $I_{\rm D}$ =46 A, $V_{\rm GS}$ =0 to 10 V	-	5	-	
Switching charge	$Q_{sw}$		-	9	-	
Gate charge total	$Q_g$		-	26	35	
Gate plateau voltage	$V_{\text{plateau}}$		-	4.9	-	V
Output charge	Q <sub>oss</sub>	$V_{DD}$ =50 V, $V_{GS}$ =0 V	-	35	46	nC
Reverse Diode						
Diode continous forward current	Is	T -25 °C	-	-	59	Α
Diode pulse current	I <sub>S,pulse</sub>	- T <sub>C</sub> =25 °C	-	-	236	
Diode forward voltage	V <sub>SD</sub>	V <sub>GS</sub> =0 V, I <sub>F</sub> =46 A, T <sub>j</sub> =25 °C	-	1	1.2	V
Reverse recovery time	t <sub>rr</sub>	V <sub>R</sub> =15 V, I <sub>F</sub> =46 A,	-	61	-	ns
Reverse recovery charge	Q <sub>rr</sub>	d <i>i<sub>F</sub></i> /d <i>t</i> =100 A/µs	_	103	_	nC

<sup>&</sup>lt;sup>6)</sup> See figure 16 for gate charge parameter definition

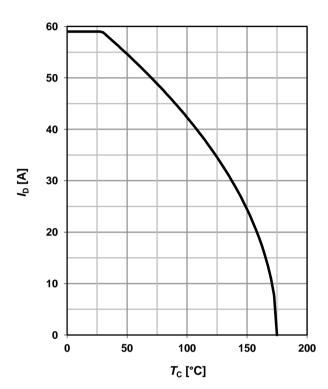


### 1 Power dissipation

## $P_{\text{tot}} = f(T_{\text{C}})$

# 100 80 60 20 20 0 50 100 150 200 T<sub>C</sub> [°C]

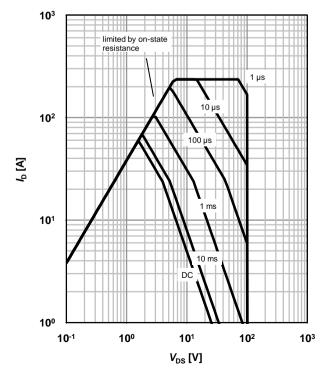
#### 2 Drain current



## 3 Safe operating area

 $I_D=f(V_{DS}); T_C=25 \text{ °C}; D=0$ 

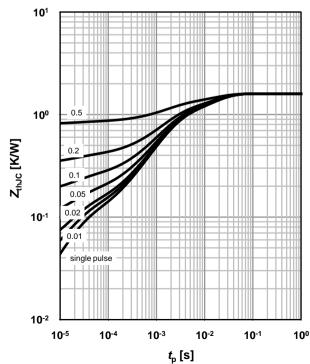
parameter:  $t_p$ 



#### 4 Max. transient thermal impedance

 $Z_{\text{thJC}}$ =f( $t_{p}$ )

parameter:  $D=t_p/T$ 

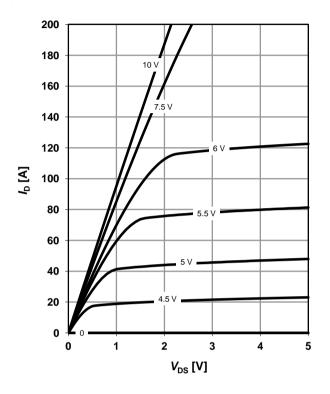




## 5 Typ. output characteristics

 $I_D=f(V_{DS}); T_j=25 °C$ 

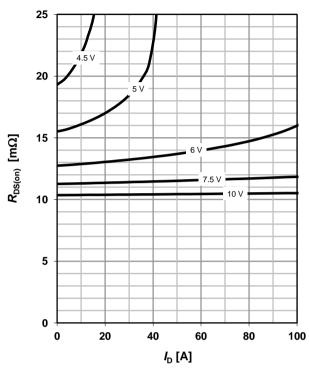
parameter: V<sub>GS</sub>



# 6 Typ. drain-source on resistance

 $R_{DS(on)}=f(I_D); T_j=25 °C$ 

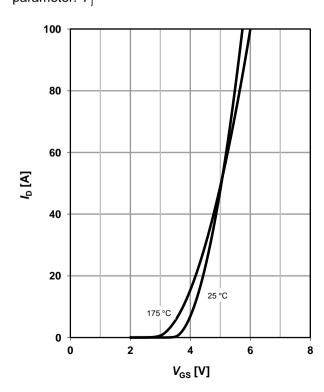
parameter: V<sub>GS</sub>



## 7 Typ. transfer characteristics

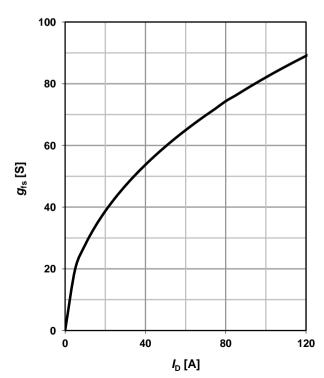
 $I_{D}=f(V_{GS}); |V_{DS}|>2|I_{D}|R_{DS(on)max}$ 

parameter:  $T_{\rm j}$ 



## 8 Typ. forward transconductance

$$g_{fs}=f(I_D); T_j=25 \text{ °C}$$





#### 9 Drain-source on-state resistance

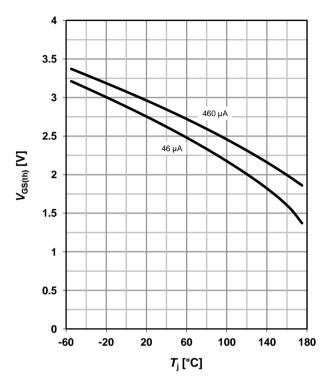
 $R_{DS(on)} = f(T_i); I_D = 46 \text{ A}; V_{GS} = 10 \text{ V}$ 

### 28 26 24 22 20 18 16 14 12 10 8 6 4 2 0 -60 -20 20 60 100 140 180 *T*<sub>j</sub> [°C]

### 10 Typ. gate threshold voltage

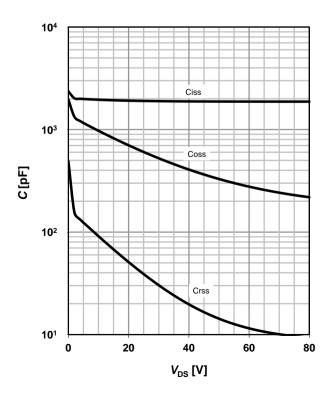
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$ 

parameter: I<sub>D</sub>



## 11 Typ. capacitances

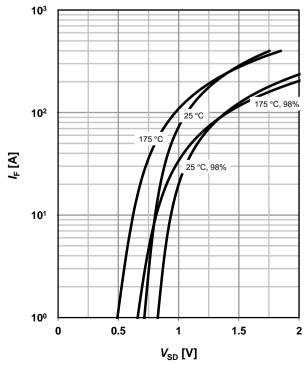
 $C=f(V_{DS}); V_{GS}=0 V; f=1 MHz$ 



#### 12 Forward characteristics of reverse diode

 $I_{\mathsf{F}} = \mathsf{f}(V_{\mathsf{SD}})$ 

parameter: T<sub>i</sub>





#### 13 Avalanche characteristics

 $I_{AS}=f(t_{AV}); R_{GS}=25 \Omega$ 

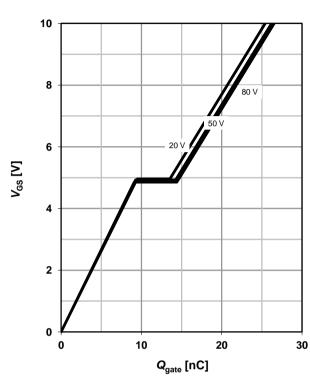
parameter:  $T_{j(start)}$ 

# 

### 14 Typ. gate charge

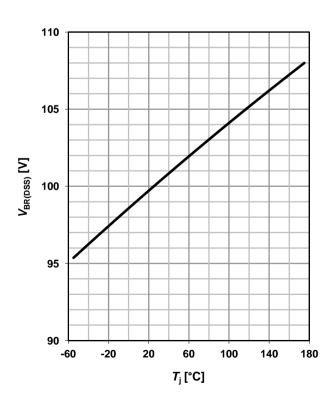
 $V_{GS}$ =f( $Q_{gate}$ );  $I_D$ =46 A pulsed

parameter:  $V_{\rm DD}$ 

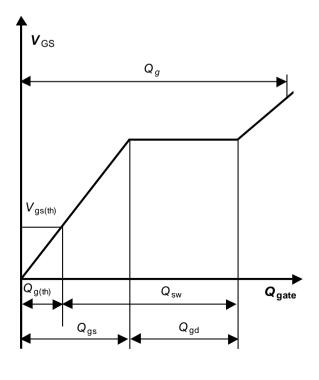


## 15 Drain-source breakdown voltage

 $V_{BR(DSS)}=f(T_j); I_D=1 \text{ mA}$ 

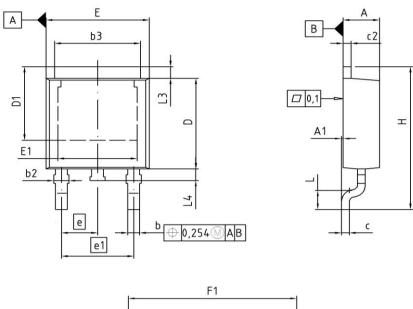


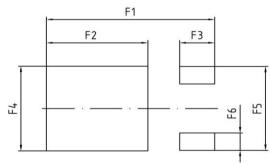
#### 16 Gate charge waveforms





## PG-TO-252 (D-Pak)





DIM	MILLIMETERS		INCHES		
DIM	MIN	MAX	MIN	MAX	
Α	2.16	2.41	0.085	0.095	
A1	0.00	0.15	0.000	0.006	
Ь	0.64	0.89	0.025	0.035	
b2	0.65	1.15	0.026	0.045	
ь3	5.00	5.50	0.197	0.217	
С	0.46	0.60	0.018	0.024	
c2	0.46	0.98	0.018	0.039	
D	5.97	6.22	0.235	0.245	
D1	5.02	5.84	0.198	0.230	
E	6.40	6.73	0.252	0.265	
E1	4.70	5.21	0.185	0.205	
е		2.29	0.	090	
e1	4.57		0.	180	
N		3		3	
Н	9.40	10.48	0.370	0.413	
L	1.18	1.70	0.046	0.067	
L3	0.90	1.25	0.035	0.049	
L4	0.51	1.00	0.020	0.039	
F1	10.50	10.70	0.413	0.421	
F2	6.30	6.50	0.248	0.256	
F3	2.10	2.30	0.083	0.091	
F4	5.70	5.90	0.224	0.232	
F5	5.66	5.86	0.223	0.231	
F6	1.10	1.30	0.043	0.051	

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2.0-1 0 2.0 14mm
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